

# **Enhancement Mode N-Channel Power MOSFET**

SOT23/NMOS/20V/ $\pm$ 12V/0.7V/3.2A/35m $\Omega$ 

Rev1.0





# 20V, $35m\Omega$ , 3.2A, N-Channel MOSFET

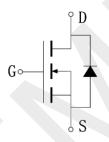
#### 1.Features

- ◆ Advanced Trench Technology
- ◆ Surface mount package
- ♦ 100% UIS Tested

- ◆ Power Management
- Load Switching



V <sub>DS</sub>	R <sub>DS(on)</sub> Typ.	I <sub>D</sub> .
20V	35mΩ @ 4.5V	2.04
	42.5mΩ @ 2.5V	3.2A



Schematic Diagram

#### 3. Package Marking and Ordering Information

Part no.	Marking	Package PCS/Reel		PCS/CTN.
WX035N02SS	A2SHB ∙	SOT23	3,000	180,000

#### 4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V <sub>DSS</sub>	20	V
Gate to Source Voltage	$V_{GSS}$	±12	V
Drain Current (DC)	ID	3.2	А
Drain Current (Pulse), PW≤300μs	I <sub>DP</sub>	12	А
Avalanche Energy, Single Pulsed	Eas	6.6	mJ
Total Dissipation	P <sub>D</sub>	0.6	W
Junction Temperature	Tj	150	°C
Storage Temperature	T <sub>stg</sub>	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



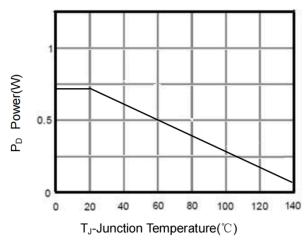
## 5.Electrical Characteristics at Ta=25°C (Note 2)

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$I_D = 250 \mu A$ , $V_{GS} = 0 V$	20	22		V
Zero-Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V			1	uA
Gate to Source Leakage Current	I <sub>GSS</sub>	$V_{GS} = \pm 12V, V_{DS} = 0V$			±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =250μA	0.4	0.7	1.2	V
Static Drain to Source On-State		I <sub>D</sub> =3.2A, V <sub>GS</sub> =4.5V		35	40	mΩ
Resistance	R <sub>DS(on)</sub>	I <sub>D</sub> =2A, V <sub>GS</sub> = 2.5V		42.5	52	mΩ
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =10V, Frequency=1.0MHz		340		pF
Output Capacitance	Coss			115		pF
Reverse Transfer Capacitance	Crss			33		pF
Turn-ON Delay Time	t <sub>d(on)</sub>	$V_{DD}$ =10V, $I_{D}$ =3A, $R_{G}$ = 6 $\Omega$ , $V_{GEN}$ = 4.5V, $R_{L}$ = 5.5 $\Omega$		12		ns
Rise Time	t <sub>r</sub>			36		ns
Turn-OFF Delay Time	$t_{\text{d(off)}}$			34		ns
Fall Time	t <sub>f</sub>			10		ns
$Q_g$ $V_{DS} = 10V$	V <sub>DS</sub> = 10V,		5.4		nC	
Total Gate Charge	Qgs	$V_{GS} = 4.5V,$ $I_{D} = 3A$		0.7		nC
	Qgd			1.6		nC
Diode Forward Voltage	V <sub>FSD</sub>	I <sub>SD</sub> =3.2A, V <sub>GS</sub> = 0	0.5	0.86	1.2	V

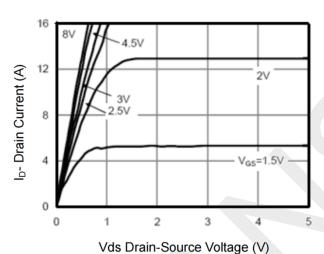
Note 2: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



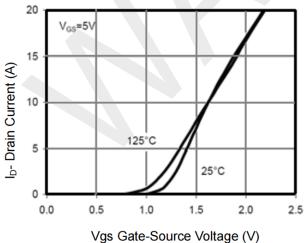
#### **6.Typical Electrical and Thermal Characteristics**



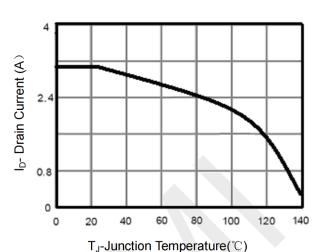
**Typical Output Characteristics** 



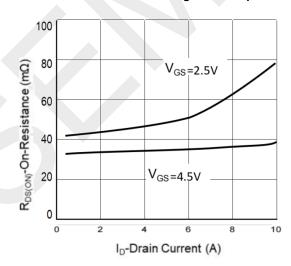
**Typical Transfer Characteristics** 



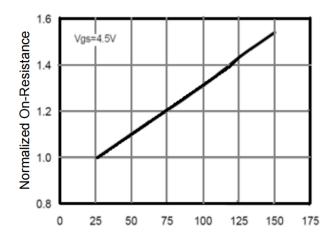
Typical Source-Drain Diode Forward Voltage



Normalized Threshold Voltage Vs. Temperature



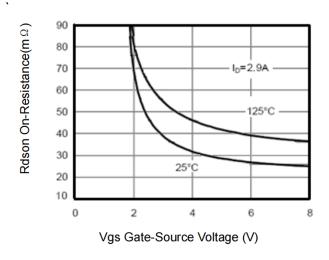
Drain -Source Voltage vs Gate -Source Voltage

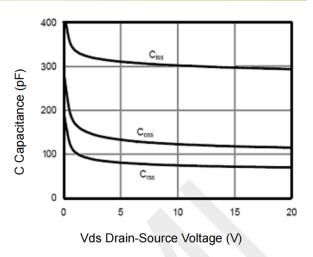


 $T_J$ -Junction Temperature( ${}^{\circ}\mathbb{C}$ )

Maximum Safe Operating Area

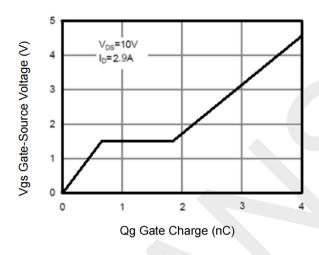


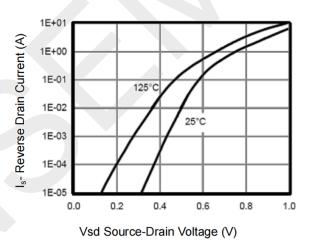




Typical Capacitance Vs. Drain-Source Voltage

Typical Gate Charge Vs. Gate-Source Voltage



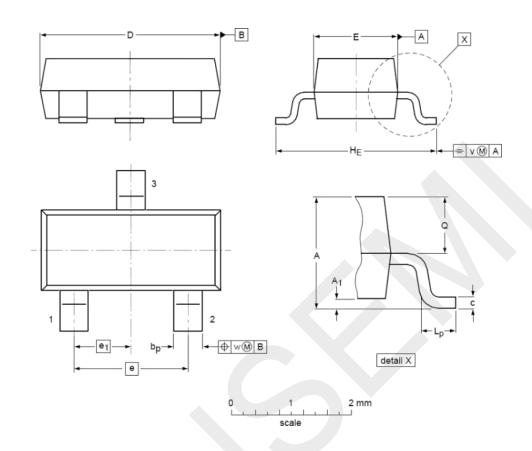


Typical Capacitance Vs. Drain-Source Voltage

Typical Gate Charge Vs. Gate-Source Voltage



## 7.Package Dimensions



DIMENSIONS ( unit : mm )

Symbol	Min	Тур	Max	Symbol	Min	Тур	Max
Α	0.90	1.01	1.15	A <sub>1</sub>	0.01	0.05	0.10
bp	0.30	0.42	0.50	С	0.08	0.13	0.15
D	2.80	2.92	3.00	E	1.20	1.33	1.40
е		1.90		e <sub>1</sub>		0.95	
HE	2.25	2.40	2.55	Lp	0.30	0.42	0.50
Q	0.45	0.49	0.55	v		0.20	
w		0.10					



#### 8.Important Notice

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